

Oven/Chamber

Intermittent Operating Life (IOL) Test System (with K-Factor Calibrator)

Manufacturer and Model

GaoKun Electronics
GK-PCx16+K-Factor

Application

Test Application:

- Device Cyclic Thermal Stress
- Degradation of Thermal Resistance (Wire Bonded Interface)

Temperature Range:

+25°C to +150°C Ageing Test (+200°C Max.)

Device Type Applicable:

Low/High Power MOSFET and IGBT

Internal Chamber Dimensions:

1620(W) x 1320(H) x 1820(D) mm

Test Capacity:

12 Modules x 40 DUTs

Test Current IM:

10mA, Accuracy +/-0.1mA

Test Pulse Width:

400usec

Device Power Supply:

12 x (24Vdc, 60A)

Picture

